

In the Specification:

On page 2, replace lines 18-28 with the following paragraph:

~According to one aspect of the present invention, there is provided a method of inspecting the surface of an article for defects by: optically examining, in a first phase examination, the complete surface of the article and electrically outputting information indicating locations on the article suspected of having defects; storing the suspected locations in a storage device; and, in a second phase examination, optically examining with high resolution only the suspected locations of the article's surface for determining the presence or absence of a defect in the suspected locations; characterized in that the first phase examination is effected by optically scanning the complete surface of the article at a high speed with an optical beam of small diameter. Thus, by selecting the diameter of the optical beam used in the first phase examination, the first phase examination may be made at any desired resolution, as compared to the second phase examination, according to the particular application.~

On page 2, line 31, after "inspected", insert --with a laser beam of small diameter--.

On page 2, line 33, before "converter", change "a" to --an image--.

On page 2, line 38, change "examining" to --examination--.

On page 3, line 5, change "examining" to --examination--.

On page 3, line 19, after "low spatial resolution" insert --such as with a laser beam of small diameter--.